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INFORMATION DISCLOSURE				Application Number	10/781,920	
				Filing Date	2/20/2004	
STATEMENT BY APPLICANT			ANT	First Named Inventor	Wunnicke, et al.	
(Use as many sheets as necessary)				Art Unit	1756	
(556 65 many shows as necessary)				Examiner Name	TBD Raymond	
Sheet	1	of	1	Attorney Docket Number	INF-138	

PTO/SB/08a (08-03)

U.S. PATENT DOCUMENTS							
Examiner Initials*	Cite No.1	Document Number	Publication Date	Name of Patentee or	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
		Number - Kind Code ^{2 (F trrown)}	MM-DD-YYYY	Applicant of Cited Document			
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NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²		
BR	3	TANAKA, T., et al., "Mechanism of Resist Pattern Collapse during Development Process," Jpn. J. Appl. Phys. Vol. 32, Part I, No. 12B, December 1993, pp. 6059-6064.			
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Examiner	R. + P	Date	10	12212	-1
Signature	Brittany Kaymand	Considered	10/	92/90	00

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